



Test and Reliability of Electronic Circuits in Natural and Radiative Environment

Luigi Dilillo

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**HABILITATION À DIRIGER DES
RECHERCHES**

**Test and Reliability of Electronic Circuits in
Natural and Radiative Environment**

Rapport de

Luigi DILILLO

Chargé de Recherche au C.N.R.S.

Mai 2015

Preamble

The researches presented in this manuscript were performed between 2002 and 2015 at the laboratory LIRMM of Montpellier (France), the University of Southampton (ECS department) and the laboratory CEA LFSE of Saclay (France). This document consists of two main parts:

- The first part is an extended Curriculum Vitae, which includes details like collaborations, supervision, teaching activities, contracts, etc.
- The second part is a summary of my research activities and perspectives ending with bibliography references and the list of my publications.

The references of which I am not the author are indicated with a number that follows the order of appearance in the text. For example, [1] and [7] denote the first and the seventh publications that are referred in the document.

A different numbering was adopted to distinguish the work to which I contributed: publications in international journals are referenced by [JO#]; publications in international conferences, symposia and workshops are referenced by [CO#], [SY#] and [WO#] respectively.

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